

# 8k × 8 Bit SRAM

## BR6265BF-N10SL

The BR6265BF-N10SL is an 8192 word × 8 bit CMOS static RAM. It runs on a 5V single power supply, and input can be directed coupled with TTL. Current dissipation in the non-selected state is extremely low at 20μA (max.), and memory information can be retained even at a low voltage of 2V, making this product ideal for battery backup operations.

Both the access and cycle timing are 100ns, facilitating timing design.

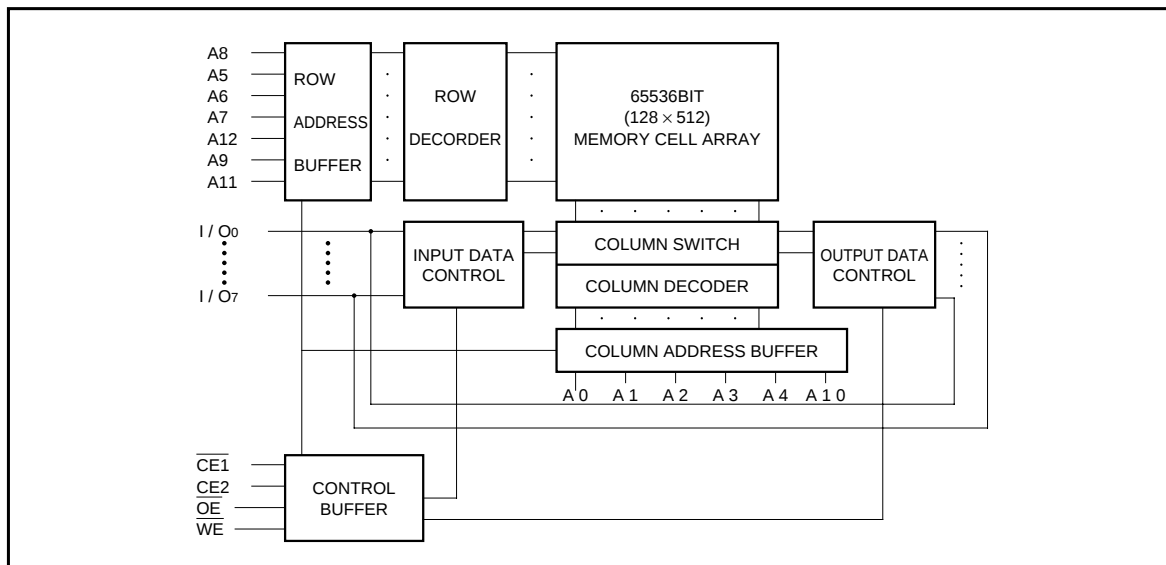
### ●Applications

General-purpose

### ●Features

- 1) SRAM with an 8192 × 8 bit configuration.
- 2) 5V single power supply voltage with ± 10% fluctuation tolerance.
- 3) High speed access time of 100ns.
- 4) TTL compatible input / output.
- 5) Input and output use the same pin, and there are 3 output states.
- 6) No clock is necessary (asynchronous static circuit).
- 7) Input and output data are in the same phase.
- 8) Low power dissipation.

### ●Block diagram



●Absolute maximum ratings (Ta = 25°C)

| Parameter             | Symbol           | Limits                        | Unit |
|-----------------------|------------------|-------------------------------|------|
| Power supply voltage  | V <sub>CC</sub>  | - 0.5*1 ~ + 7.0               | V    |
| Power dissipation     | P <sub>d</sub>   | 850*2                         | mW   |
| Operating temperature | T <sub>opr</sub> | 0 ~ 70                        | °C   |
| Storage temperature   | T <sub>stg</sub> | - 55 ~ + 125                  | °C   |
| I / O voltage         | V <sub>I</sub>   | - 0.5 ~ V <sub>CC</sub> + 0.5 | V    |

\*1 At pulse width of 50 ns : - 3.0V (min.)

\*2 Reduced by 8.5mW for each increase in Ta of 1°C over 25°C.

●Recommended operating conditions (Ta = 25°C)

| Parameter                | Symbol          | Min.  | Typ. | Max.                  | Unit |
|--------------------------|-----------------|-------|------|-----------------------|------|
| Power supply voltage     | V <sub>CC</sub> | 4.5   | 5.0  | 5.5                   | V    |
| Input high level voltage | V <sub>IH</sub> | 2.2   | —    | V <sub>CC</sub> + 0.5 | V    |
| Input low level voltage  | V <sub>IL</sub> | - 0.3 | —    | 0.8                   | V    |
| Ambient temperature      | Ta              | 0     | —    | 70                    | °C   |

●Pin descriptions

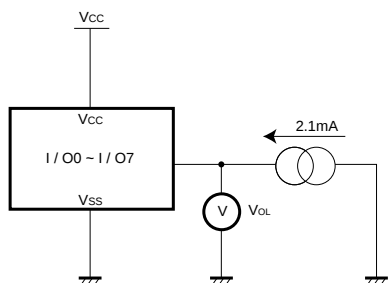
| Pin No.                | Pin name                | Function                                     |
|------------------------|-------------------------|----------------------------------------------|
| 1                      | NC                      | Internal chip and not connected              |
| 2 ~ 10, 21,<br>23 ~ 25 | A0 ~ A12                | 8192-byte memory address input               |
| 11 ~ 13,<br>15 ~ 19    | I / O0 ~ I / O7         | 8-bit data I / O                             |
| 20                     | $\overline{\text{CE}}1$ | Chip enable control input                    |
| 26                     | CE2                     | Chip enable control input                    |
| 22                     | $\overline{\text{OE}}$  | Output enable control input                  |
| 27                     | $\overline{\text{WE}}$  | Write enable control input                   |
| 28                     | V <sub>CC</sub>         | 5V ± 10% power supply                        |
| 14                     | V <sub>SS</sub>         | Reference voltage for all input / output, 0V |

●Electrical characteristics (unless otherwise noted, Ta = 0 to 70°C, V<sub>CC</sub> = 5V ± 10%)

| Parameter                 | Symbol            | Min.                  | Typ. | Max.                  | Unit | Conditions                                                                             | Measurement circuit |
|---------------------------|-------------------|-----------------------|------|-----------------------|------|----------------------------------------------------------------------------------------|---------------------|
| Input low level voltage   | V <sub>IL</sub>   | − 0.3*1               | —    | 0.8                   | V    | —                                                                                      | —                   |
| Input high level voltage  | V <sub>IH</sub>   | 2.2                   | —    | V <sub>CC</sub> + 0.5 | V    | —                                                                                      | —                   |
| Output low level voltage  | V <sub>OL</sub>   | 0                     | —    | 0.4                   | V    | I <sub>OL</sub> = 2.1mA                                                                | Fig.1               |
| Output high level voltage | V <sub>OH</sub>   | 2.4                   | —    | V <sub>CC</sub>       | V    | I <sub>OH</sub> = − 1.0mA                                                              | Fig.2               |
|                           |                   | V <sub>CC</sub> × 0.8 | —    | V <sub>CC</sub>       | V    | I <sub>OH</sub> = − 0.1mA                                                              | —                   |
| Input leakage current     | I <sub>LI</sub>   | —                     | —    | ± 1                   | μA   | V <sub>IN</sub> = 0 ~ V <sub>CC</sub>                                                  | Fig.3               |
| Output leakage current    | I <sub>LO</sub>   | —                     | —    | ± 1                   | μA   | V <sub>OUT</sub> = 0 ~ V <sub>CC</sub>                                                 | Fig.4               |
| Average operating current | I <sub>CCA1</sub> | —                     | —    | 40                    | mA   | $\overline{CE1} = V_{IL}$ , CE2 = V <sub>IH</sub> , I / O: OPEN<br>Minimum cycle time  | Fig.5               |
|                           | I <sub>CCA2</sub> | —                     | —    | 10                    | mA   | $\overline{CE1} = V_{IL}$ , CE2 = V <sub>IH</sub> , I / O: OPEN<br>f = 1MHz            | Fig.5               |
| Standby current           | I <sub>SB</sub>   | —                     | —    | 3                     | mA   | $\overline{CE1} = V_{IH}$ or CE2 = V <sub>IL</sub>                                     | —                   |
|                           | I <sub>SB1</sub>  | —                     | —    | 20                    | μA   | $\overline{CE1} \cong V_{CC} - 0.2V$ ,<br>CE2 $\cong V_{CC} - 0.2V$ or CE2 $\leq 0.2V$ | Fig.6               |
|                           | I <sub>SB2</sub>  | —                     | —    | 20                    | μA   | CE2 $\leq 0.2V$                                                                        | —                   |

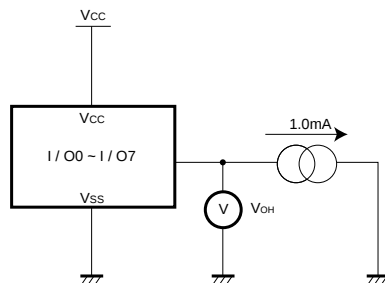
\*1 At input voltage pulse width of 50 ns or less : − 3.0V

## ● Measurement circuits



Data sets all output to LOW (Data 00)

Fig. 1 Output low level voltage measurement circuit



Data sets all output to HIGH (Data FF)

Fig. 2 Output high level voltage measurement circuit

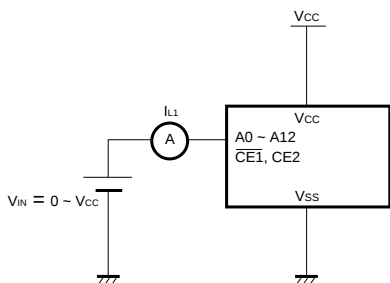


Fig. 3 Input leakage measurement circuit

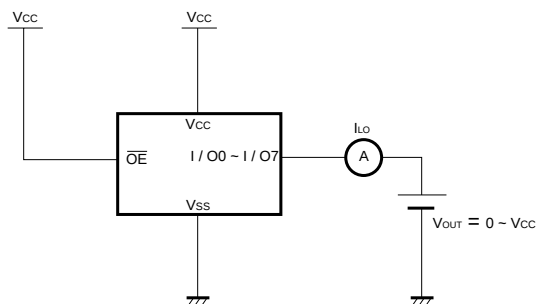


Fig. 4 Output leakage current measurement circuit

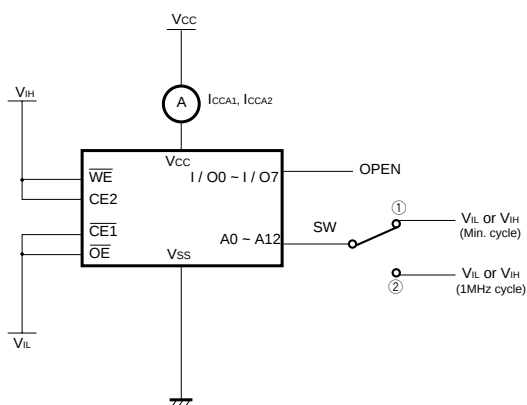
① : Average operating current I<sub>CCA1</sub>② : Average operating current I<sub>CCA2</sub>

Fig. 5 Current dissipation measurement circuit

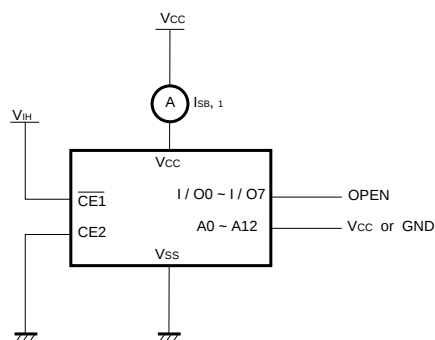


Fig. 6 Standby current measurement circuit

## ● Operating modes

| Control pin            |                         |     |                        | Mode            | I / O          | Power dissipation |
|------------------------|-------------------------|-----|------------------------|-----------------|----------------|-------------------|
| $\overline{\text{OE}}$ | $\overline{\text{CE1}}$ | CE2 | $\overline{\text{WE}}$ |                 |                |                   |
| X                      | H                       | X   | X                      | Wait state      | High impedance | Standby state     |
| X                      | X                       | L   | X                      | Wait state      | High impedance | Standby state     |
| H                      | L                       | H   | H                      | Output disabled | High impedance | Operating state   |
| L                      | L                       | H   | H                      | Read            | Data output    | Operating state   |
| X                      | L                       | H   | L                      | Write           | Data output    | Operating state   |

X : Either  $V_{\text{IL}}$  or  $V_{\text{IH}}$ ● AC test conditions ( $T_a = 0$  to  $70^\circ\text{C}$ ,  $V_{\text{CC}} = 5\text{V} \pm 10\%$ )

Input pulse level : 0.8 to 2.4V

Input rise / fall time : 5ns

I / O timing level : 1.5V

Output load : 1 TTL gate and  $C_L = 100\text{pF}$ 

## ● Read cycle

| Parameter                                        | Symbol           | Min. | Max. | Unit |
|--------------------------------------------------|------------------|------|------|------|
| Read cycle time                                  | $t_{\text{RC}}$  | 100  | —    | ns   |
| Address access time                              | $t_{\text{AA}}$  | —    | 100  | ns   |
| $\overline{\text{CE1}}$ access time              | $t_{\text{CO1}}$ | —    | 100  | ns   |
| CE2 access time                                  | $t_{\text{CO2}}$ | —    | 100  | ns   |
| $\overline{\text{OE}}$ access time               | $t_{\text{OE}}$  | —    | 40   | ns   |
| Output hold time                                 | $t_{\text{OH}}$  | 10   | —    | ns   |
| $\overline{\text{CE1}}$ output set time          | $t_{\text{LZ1}}$ | 10   | —    | ns   |
| CE2 output set time                              | $t_{\text{LZ2}}$ | 10   | —    | ns   |
| $\overline{\text{OE}}$ output reset time         | $t_{\text{OLZ}}$ | 5    | —    | ns   |
| $\overline{\text{CE1}}$ deselect output floating | $t_{\text{HZ1}}$ | —    | 35   | ns   |
| $\overline{\text{CE2}}$ deselect output floating | $t_{\text{HZ2}}$ | —    | 35   | ns   |
| $\overline{\text{OE}}$ disable output floating   | $t_{\text{OHZ}}$ | —    | 35   | ns   |

●Read cycle timing chart 2 ( $\overline{WE} = V_{IH}$ )

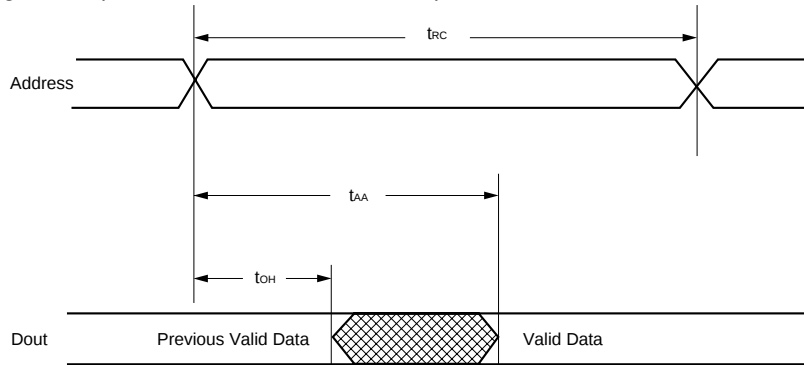
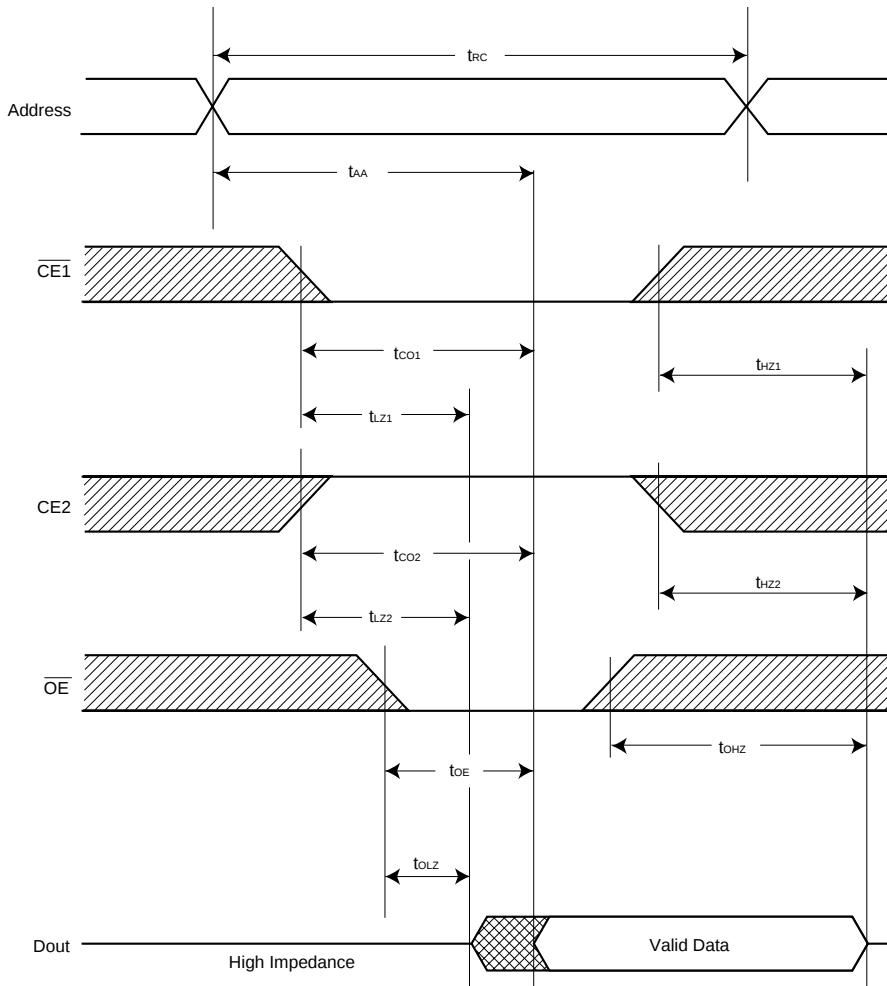


Fig.7

●Read cycle timing chart 2 ( $\overline{WE} = V_{IH}$ )



Fgi.8

## ●Write cycle

| Parameter                                             | Symbol    | Min. | Max. | Unit |
|-------------------------------------------------------|-----------|------|------|------|
| Write cycle time                                      | $t_{WC}$  | 100  | —    | ns   |
| Chip select time                                      | $t_{CW}$  | 80   | —    | ns   |
| Address valid time                                    | $t_{AW}$  | 80   | —    | ns   |
| Address setup time                                    | $t_{AS}$  | 0    | —    | ns   |
| Write pulse width                                     | $t_{WP}$  | 60   | —    | ns   |
| $\overline{WE}$ output delay time                     | $t_{WR}$  | 0    | —    | ns   |
| $\overline{CE1}$ , $\overline{CE2}$ output delay time | $t_{WR1}$ | 0    | —    | ns   |
| $\overline{WE}$ · output floating time                | $t_{WHZ}$ | —    | 35   | ns   |
| Input data set time                                   | $t_{DW}$  | 40   | —    | ns   |
| Input data hold time                                  | $t_{DH}$  | 0    | —    | ns   |
| $\overline{WE}$ · output set time                     | $t_{OW}$  | 5    | —    | ns   |

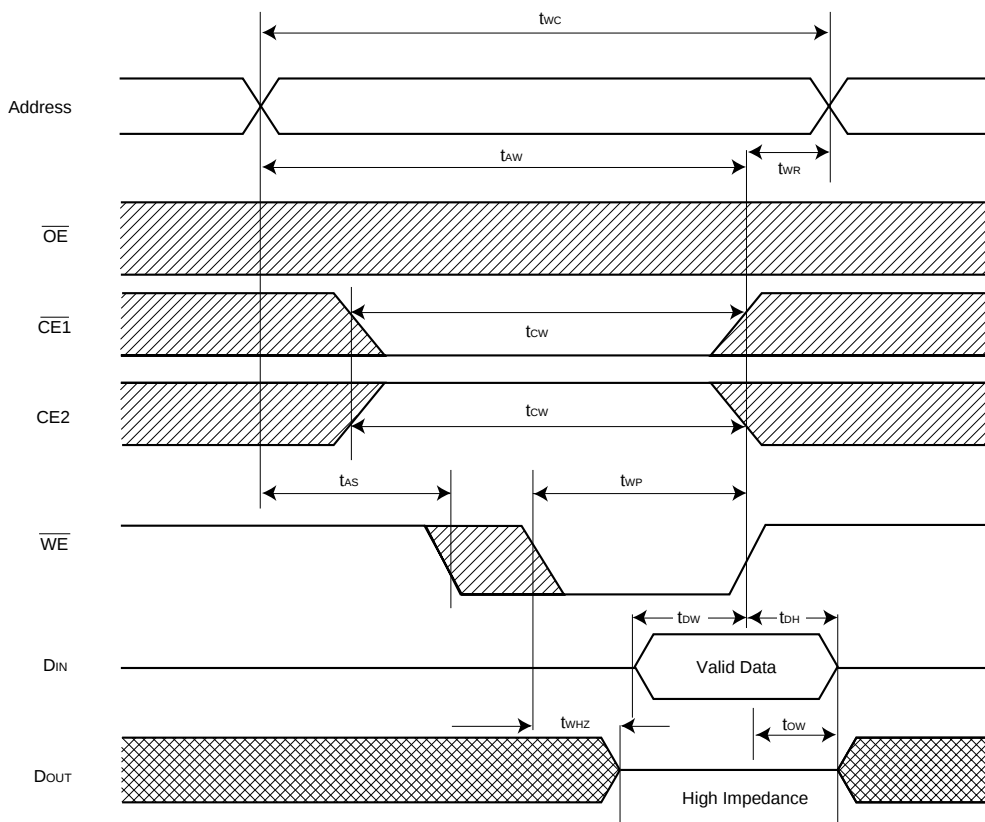
●Write cycle timing chart 1 ( $\overline{WE}$  control)

Fig.9

● Write cycle timing chart 2 ( $\overline{\text{CE1}}$  control)

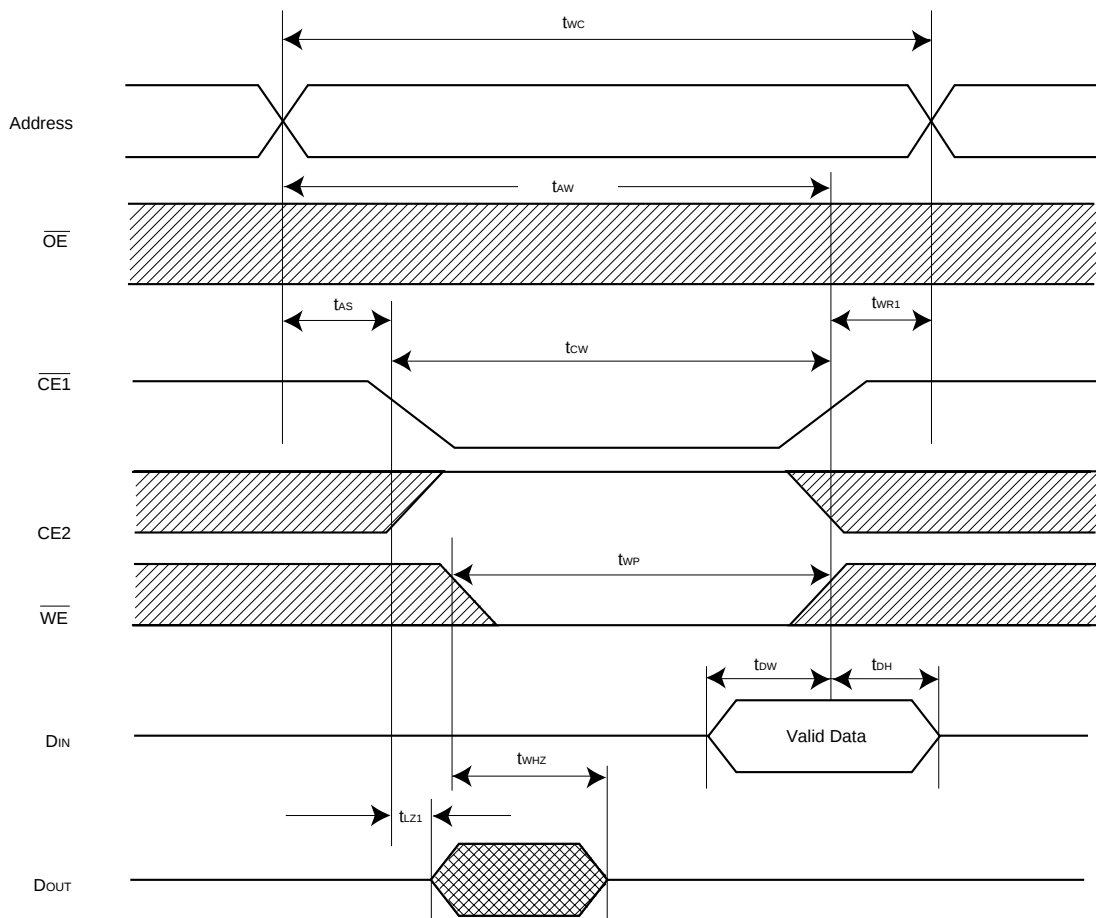


Fig.10

● Write cycle timing chart 3 (CE2 control)

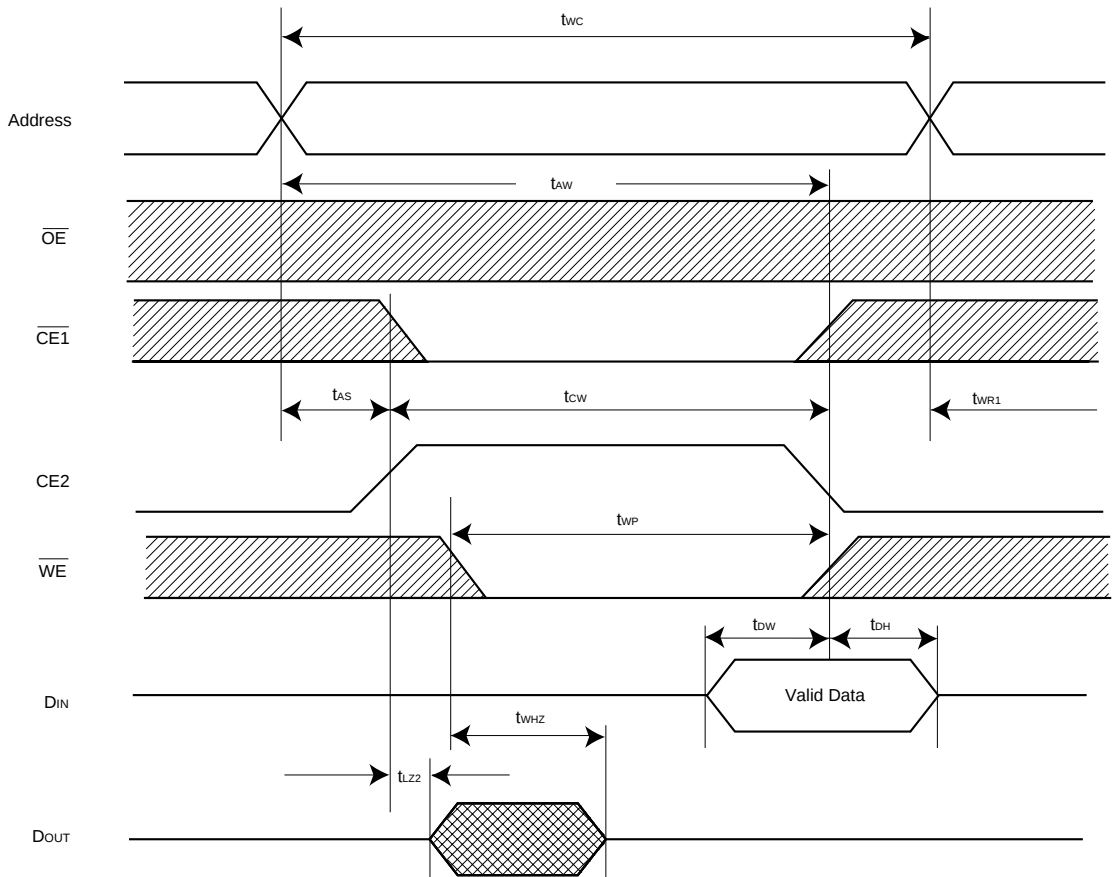


Fig.11

- \* While the I / O pin is in output state, input signals should not be applied which are in reverse phase to the output.
- \* The contents noted in this document may fall under the jurisdiction of services pertaining to overseas exchange rates and overseas control regulations (services pertaining to design, construction, specifications), and may require special handling.

● Data retention characteristics at low power supply voltage ( $T_a = 0$  to  $70^\circ\text{C}$ ): SL version products

| Parameter                           | Symbol       | Min. | Typ. | Max. | Unit          | Conditions                                                                                                                         |
|-------------------------------------|--------------|------|------|------|---------------|------------------------------------------------------------------------------------------------------------------------------------|
| Data retention power supply voltage | $V_{DR}$     | 2.0  | —    | 5.5  | V             | $\overline{CE1} \geq V_{CC} - 0.2\text{V}$ , $CE2 \geq V_{CC} - 0.2\text{V}$<br>or $CE2 \leq 0.2\text{V}$                          |
| Data retention current              | $I_{CCDR}^*$ | —    | —    | 10   | $\mu\text{A}$ | $\overline{CE1} \geq V_{CC} - 0.2\text{V}$ , $CE2 \geq V_{CC} - 0.2\text{V}$<br>or $CE2 \leq 0.2\text{V}$ , $V_{CC} = 3.0\text{V}$ |
| CS data retention time              | $t_{CDR}$    | 0    | —    | —    | ns            | —                                                                                                                                  |
| Operating recovery time             | $t_R$        | 5    | —    | —    | ms            | —                                                                                                                                  |

\*  $1\mu\text{A}$  (Max.), when  $T_a = 0 \sim 40^\circ\text{C}$

● Data retention waveform at low power supply voltage

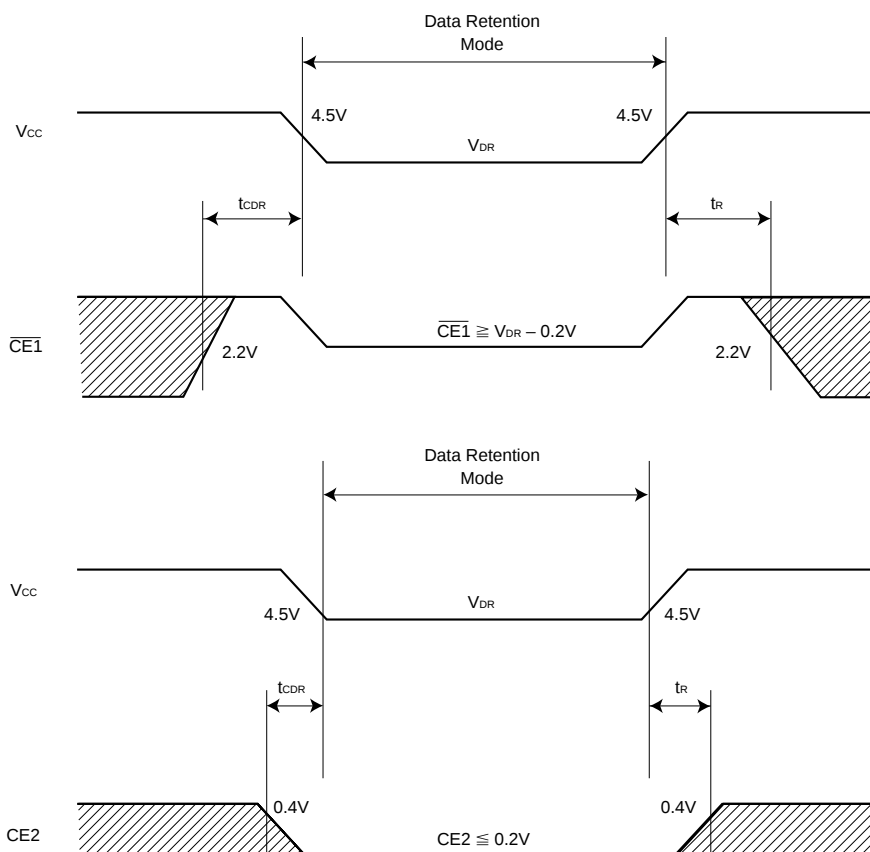
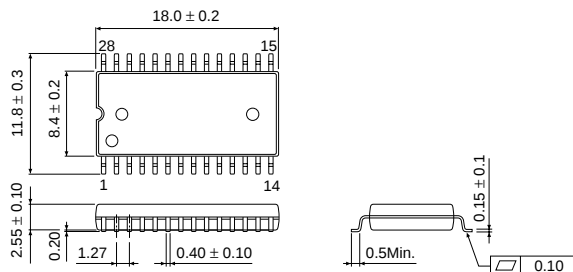


Fig.12

## ● External dimensions (Units: mm)



SOP-N28